


Search Notes 	Application/Control No. 10524715	Applicant(s)/Patent Under Reexamination LEE ET AL.
	Examiner Nguyen, Hai V	Art Unit 2618

SEARCHED			
Class	Subclass	Date	Examiner
725	32	01/23/2008	HN
455	3.01	02/06/2008	HN

SEARCH NOTES		
Search Notes	Date	Examiner
EAST search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) (see search history printout report)	02/05/2008	HN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner